16. TEST SETUP PHOTOGRAPHS

FCC ID: A3LSMA600T		HAC (T-COIL) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Page 69 of 71
1M1808210161-12-R1.A3L	08/22/2018 - 08/28/2018	Portable Handset		Fage 05 0171
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04/17/2018



Figure 16-1 Test Setup for Wireless Device

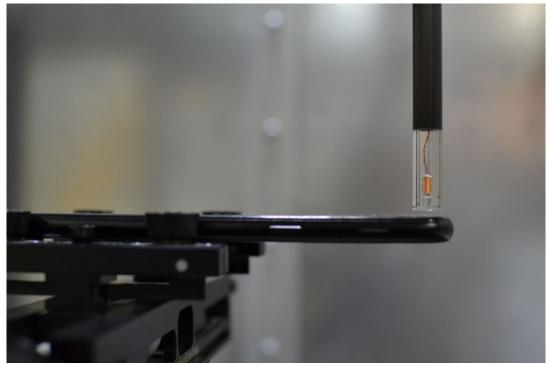


Figure 16-2 Test Setup for Wireless Device

FCC ID: A3LSMA600T		HAC (T-COIL) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Page 70 of 71
1M1808210161-12-R1.A3L	08/22/2018 - 08/28/2018	Portable Handset		Faye / V UI / I
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Figure 16-3 T-Coil Scan Overlay Magnetic Field Distributions

Note: Final measurement locations are indicated by a cursor on the contour plots.

FCC ID: A3LSMA600T		HAC (T-COIL) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Page 71 of 71
1M1808210161-12-R1.A3L	08/22/2018 - 08/28/2018	Portable Handset		
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